

# iCE40™ LP Series Ultra Low-Power mobileFPGA™ Family



March 30, 2012 (1.31)

Data Sheet

- **LP-Series - Smartphone targeted series optimized for low power**
- **Ultra-small footprints**
- **30% faster than iCE65**
- **Smartphone convergence HD video image**
- **Proven, high-volume 40 nm, low-power CMOS technology**
- **Integrated Phase-Locked Loop (PLL)**
  - ◆ Clock multiplication/division for display, SerDes and memory interface applications
- **Up to 533 MHz PLL Output**
- **Reprogrammable from a variety of methods and sources**
- **Flexible programmable logic and programmable interconnect fabric**
  - ◆ 8K look-up tables (LUT4) and flip-flops
  - ◆ Low-power logic and interconnect
- **Complete iCEcube2™ development system**
  - ◆ Windows® and Linux® support
  - ◆ VHDL and Verilog logic synthesis
  - ◆ Place and route software
  - ◆ Design and IP core libraries
  - ◆ Low-cost iCEman40LP development board

Figure 1: iCE40 LP-Series Family Architectural Features

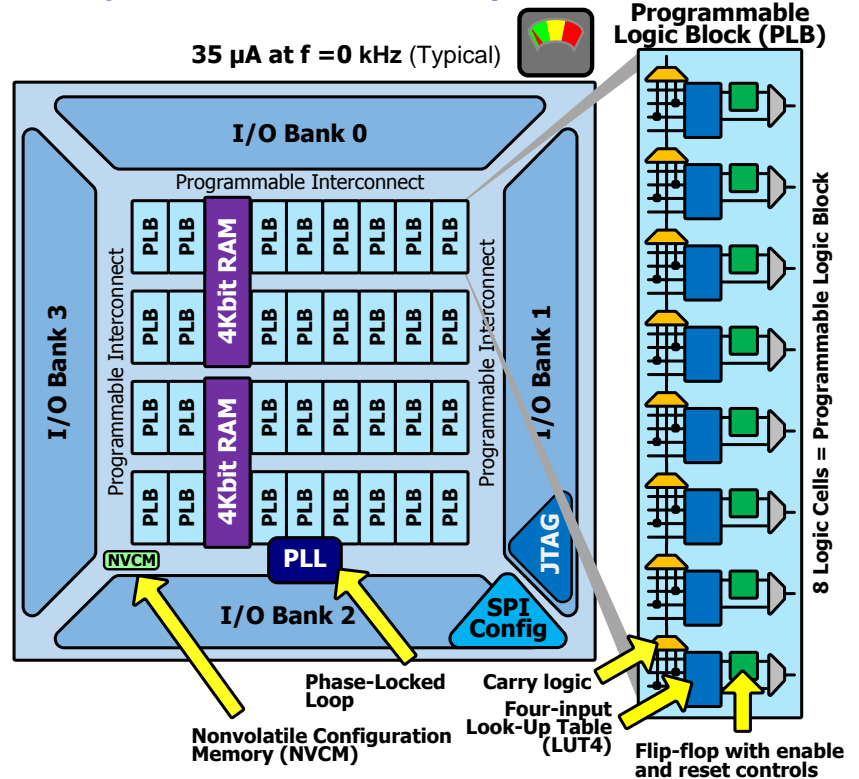


Table 1: iCE40LP Ultra Low-Power Programmable Logic Family Summary

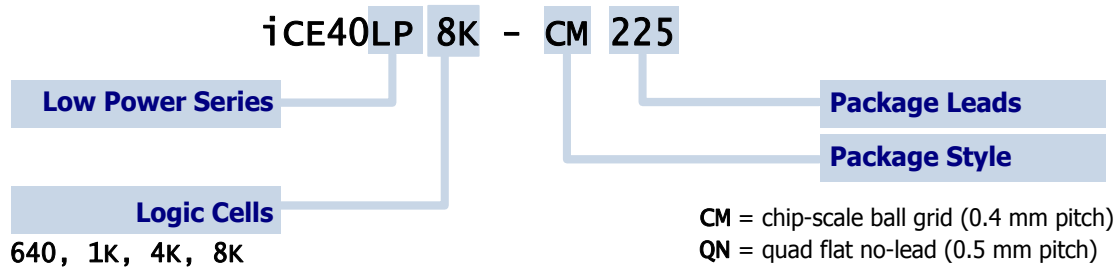
Part Number		LP640	LP1K	LP4K	LP8K
<b>Logic Cells (LUT + Flip-Flop)</b>		640	1,280	3,520	7,680
<b>RAM4K Memory Blocks</b>		8	16	20	32
<b>RAM4K RAM bits</b>		32K	64K	80K	128K
<b>Phase-Locked Loops (PLLs)</b>		1	1	2	2
<b>Configuration bits (maximum)</b>		120 Kb	245 Kb	533 Kb	1,057 Kb
<b>Core Operating Power 0 KHz<sup>1</sup></b>		35 µA	40 µA	140 µA	160 µA
<b>Maximum Programmable I/O Pins</b>		63	95	167	178
<b>Maximum Differential Input Pairs</b>		8	12	20	23
Package	Code	Area mm	Pitch mm	Programmable I/O: Max I/O (LVDS)	
36 <sup>2</sup> -ball chip-scale	CM36	2.5x2.5	0.4	25(3)	25(3)
49-ball chip-scale BGA	CM49	3x3	0.4	35(5)	35(5)
81-ball chip-scale BGA	CM81	4x4	0.4	63(8)	63(8)
121-ball chip-scale	CM121	5x5	0.4	95 (12)	93 (13)
225-ball chip-scale	CM225	7x7	0.4		167 (20)
84 <sup>2</sup> -pin quad no-lead	QN84	7x7	0.5	67(7)	

Note 1: At 1.2V VCC Note 2: No PLL Available Note 3: Only 1 PLL Available

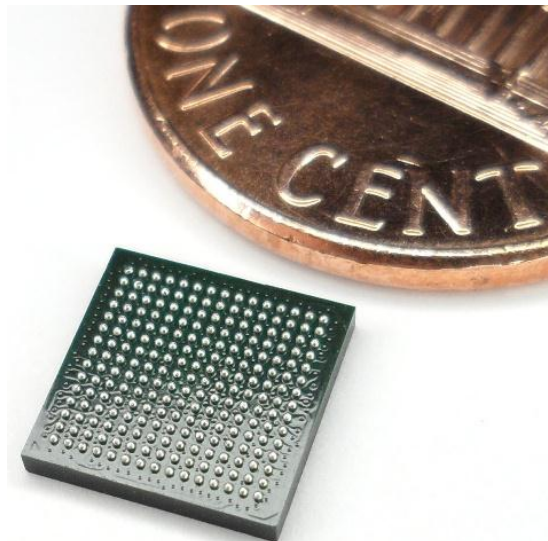
## Ordering Information

Figure 2 describes the iCE40LP ordering codes for all packaged components. See the separate DiePlus data sheets when ordering die-based products. See the separate iCE40 Pinout Excel files for package and pinout specifications.

Figure 2: iCE40P Ordering Codes (packaged, non-die components)



iCE40LP8K-CM225  
225-ball Chip-Scale BGA Package  
(7x7 mm footprint, 0.4 mm pitch)



## Electrical Characteristics

All parameter limits are specified under worst-case supply voltage, junction temperature, and processing conditions.

### Absolute Maximum Ratings

Stresses beyond those listed under [Table 2](#) may cause permanent damage to the device. These are stress ratings only; functional operation of the device at these or any other conditions beyond those listed under the Recommended Operating Conditions is not implied. Exposure to absolute maximum conditions for extended periods of time adversely affects device reliability.

*Table 2: Absolute Maximum Ratings*

Symbol	Description	Minimum	Maximum	Units
<b>VCC</b>	Core supply Voltage	-0.5	1.42	V
<b>VPP_2V5</b>	VPP_2V5 NVCM programming and operating supply			V
<b>VPP_FAST</b>	Optional fast NVCM programming supply			V
<b>VCCIO_0</b> <b>VCCIO_1</b> <b>VCCIO_2</b> <b>VCCIO_3</b> <b>SPI_VCC</b>	I/O bank supply voltage (I/O Banks 0, 1, 2 and 3 plus SPI interface)	-0.5	4.00	V
<b>VIN_0</b> <b>VIN_1</b> <b>VIN_2</b> <b>VIN_SPI</b> <b>VIN_3</b>	Voltage applied to PIO pin within a specific I/O bank (I/O Banks 0, 1, 2 and 3 plus SPI interface)	-1.0	3.6	V
<b>VCCPLL</b>	Analog voltage supply to the Phase Locked Loop (PLL)	-0.5	1.30	V
<b>I<sub>OUT</sub></b>	DC output current per pin	—	20	mA
<b>T<sub>J</sub></b>	Junction temperature	-55	125	°C
<b>T<sub>STG</sub></b>	Storage temperature, no bias	-65	150	°C

### Recommended Operating Conditions

*Table 3: Recommended Operating Conditions*

Symbol	Description		Minimum	Nominal	Maximum	Units
VCC	Core supply voltage	High Performance, low-power	1.14	1.20	1.26	V
VPP_2V5 <sup>1</sup>	VPP_2V5 NVCM programming and operating supply	Release from Power-on Reset	1.30	—	3.47	V
		Configure from NVCM	2.30	—	3.47	V
		NVCM programming	2.30	—	3.00	V
VPP_FAST <sup>2</sup>	Optional fast NVCM programming supply	Leave unconnected in application				
SPI_VCC	SPI interface supply voltage		1.71	—	3.47	V
VCCIO_0 VCCIO_1 VCCIO_2 VCCIO_3 SPI_VCC	I/O standards, all banks	<b>LVC MOS33</b>	2.70	3.30	3.47	V
		<b>LVC MOS25, LVDS</b>	2.38	2.50	2.63	V
		<b>LVC MOS18, SubLVDS</b>	1.71	1.80	1.89	V
		<b>LVC MOS15</b>	1.43	1.50	1.58	V
<b>VCCPLL</b> <sup>3</sup>	Analog voltage supply to the Phase Locked Loop (PLL)		1.14	1.20	1.26	V
T <sub>A</sub>	Ambient temperature		-40	—	85	°C
T <sub>PROG</sub>	NVCM programming temperature		10	25	30	°C

#### Notes:

- VPP\_2V5 must be connected to a valid voltage, when the iCE40LP device is active.
- VPP\_FAST, used only for fast production programming, must be left floating or unconnected in application, except CM36 and CM49 packages MUST have VPP\_FAST ball connected to VCCIO\_0 ball externally.
- VCCPLL must be tied to VCC when PLL is not used.

## I/O Characteristics

Table 4: PIO Pin Electrical Characteristics

Symbol	Description	Conditions	Minimum	Nominal	Maximum	Units
<b>I<sub>I</sub></b>	Input pin leakage current	$V_{IN} = V_{CCIO_{max}}$ to 0 V			±10	μA
<b>I<sub>OZ</sub></b>	Three-state I/O pin (Hi-Z) leakage current	$V_O = V_{CCIO_{max}}$ to 0 V			±10	μA
<b>C<sub>PIO</sub></b>	PIO pin input capacitance			6		pF
<b>C<sub>GBIN</sub></b>	GBIN global buffer pin input capacitance			6		pF
<b>R<sub>PULLUP</sub></b>	Internal PIO pull-up resistance during configuration	$V_{CCIO} = 3.3V$		60		kΩ
		$V_{CCIO} = 2.5V$		80		kΩ
		$V_{CCIO} = 1.8V$		120		kΩ
		$V_{CCIO} = 1.5V$		160		kΩ
<b>V<sub>HYST</sub></b>	Input hysteresis	$V_{CCIO} = 1.5V$ to 3.3V		50		mV

**NOTE:** All characteristics are characterized and may or may not be tested on each pin on each device.

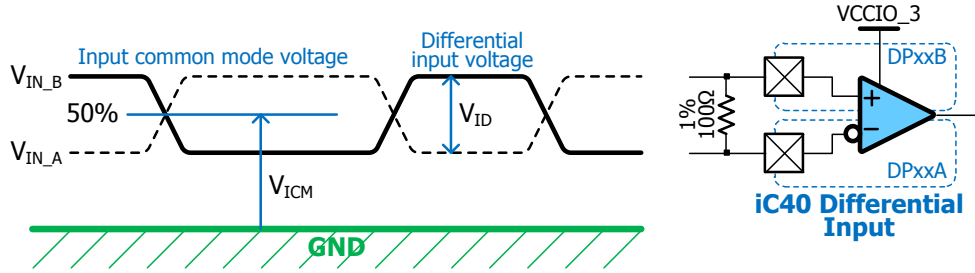
## Single-ended I/O Characteristics

Table 5: I/O Characteristics

I/O Standard	Nominal I/O Bank Supply Voltage	Input Voltage (V)		Output Voltage (V)		Output Current at Voltage (mA)	
		$V_{IL}$	$V_{IH}$	$V_{OL}$	$V_{OH}$	$I_{OL}$	$I_{OH}$
LVC MOS33	3.3V	0.80	2.00	0.4	2.40	8	8
LVC MOS25	2.5V	0.70	1.70	0.4	2.00	6	6
LVC MOS18	1.8V	35% VCCIO	65% VCCIO	0.4	1.40	4	4
LVC MOS15	1.5V	35% VCCIO	65% VCCIO	0.4	1.20	2	2

Differential Inputs

Figure 3: Differential Input Specifications



Input common mode voltage:

$$V_{ICM} = \frac{VCCIO\_3}{2} \pm \Delta V_{ICM}$$

Differential input voltage:

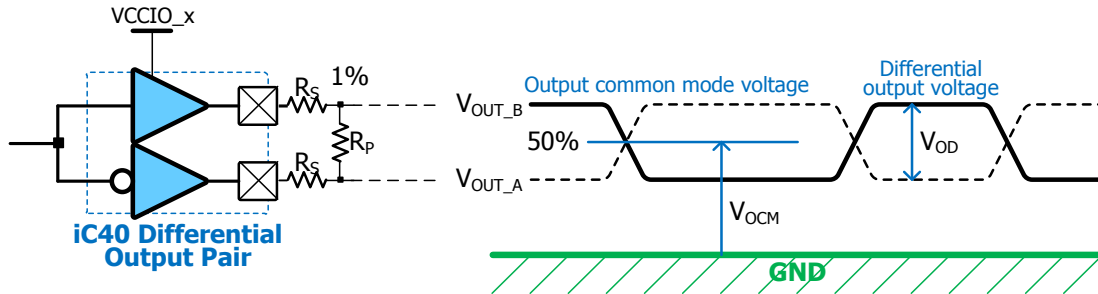
$$V_{ID} = |V_{IN\_B} - V_{IN\_A}|$$

Table 6: Recommended Operating Conditions for Differential Inputs

I/O Standard	VCCIO_3 (V)			V <sub>ID</sub> (mV)			V <sub>ICM</sub> (V)		
	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max
<b>LVDS</b>	2.38	2.50	2.63	250	350	450	$\frac{VCCIO\_3}{2} - 0.30$	$\frac{VCCIO\_3}{2}$	$\frac{VCCIO\_3}{2} + 0.30$
<b>SubLVDS</b>	1.71	1.80	1.89	100	150	200	$\frac{VCCIO\_3}{2} - 0.25$	$\frac{VCCIO\_3}{2}$	$\frac{VCCIO\_3}{2} + 0.25$

Differential Outputs

Figure 4: Differential Output Specifications



Output common mode voltage:

$$V_{OCM} = \frac{VCCIO\_x}{2} \pm \Delta V_{OCM}$$

Differential output voltage:

$$V_{OD} = |V_{OUT\_B} - V_{OUT\_A}|$$

Table 7: Recommended Operating Conditions for Differential Outputs

I/O Standard	VCCIO_x (V)			Ω		V <sub>OD</sub> (mV)			V <sub>OCM</sub> (V)		
	Min	Nom	Max	R <sub>S</sub>	R <sub>P</sub>	Min	Nom	Max	Min	Nom	Max
<b>LVDS</b>	2.38	2.50	2.63	150	140	300	350	400	$\frac{VCCIO}{2} - 0.15$	$\frac{VCCIO}{2}$	$\frac{VCCIO}{2} + 0.15$
<b>SubLVDS</b>	1.71	1.80	1.89	270	120	100	150	200	$\frac{VCCIO}{2} - 0.10$	$\frac{VCCIO}{2}$	$\frac{VCCIO}{2} + 0.10$

## AC Timing Guidelines

The following examples provide some guidelines of device performance. The actual performance depends on the specific application and how it is physically implemented in the iCE65P FPGA using the Lattice iCEcube2 software. The following guidelines assume typical conditions (VCC = 1.0 V or 1.2 V as specified, temperature = 25 °C). Apply derating factors using the iCEcube2 timing analyzer to adjust to other operating regimes.

### Programmable Logic Block (PLB) Timing

Table 8 provides timing information for the logic in a Programmable Logic Block (PLB), which includes the paths shown in Figure 5 and Figure 6.

Figure 5 PLB Sequential Timing Circuit

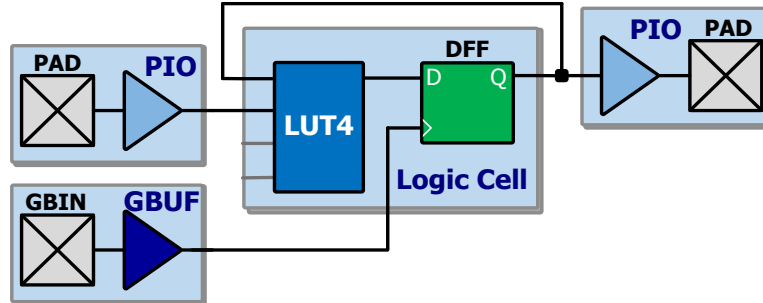


Figure 6 PLB Combinational Timing Circuit

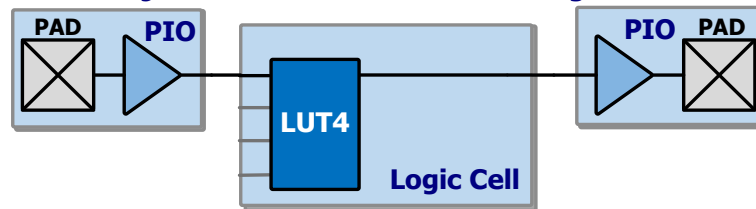


Table 8: Typical Programmable Logic Block (PLB) Timing

			Nominal VCC	1.2 V	
Description				Typ.	units
<b>Sequential Logic Paths</b>					
<b>F<sub>TOGGLE</sub></b>	GBIN input	GBIN input	Flip-flop toggle frequency. DFF flip-flop output fed back to LUT4 input with 4-input XOR, clocked on same clock edge	256	MHz
<b>t<sub>CKO</sub></b>	DFF clock input	PIO output	Logic cell flip-flop (DFF) clock-to-output time, measured from the DFF CLK input to PIO output, including interconnect delay.	5.5	ns
<b>t<sub>GBCKLC</sub></b>	GBIN input	DFF clock input	Global Buffer Input (GBIN) delay, through Global Buffer (GBUF) clock network to clock input on the logic cell DFF flip-flop.	2.1	ns
<b>t<sub>SULT</sub></b>	PIO input	GBIN input	Minimum setup time on PIO input, through LUT4, to DFF flip-flop D-input before active clock edge on the GBIN input, including interconnect delay.	0.9	ns
<b>t<sub>HDLI</sub></b>	GBIN input	PIO input	Minimum hold time on PIO input, through LUT4, to DFF flip-flop D-input after active clock edge on the GBIN input, including interconnect delay.	0	ns
<b>Combinational Logic Paths</b>					
<b>t<sub>LUT4IN</sub></b>	PIO input	LUT4 input	Asynchronous delay from PIO input pad to adjacent PLB interconnect.	2.5	ns
<b>t<sub>LO</sub></b>	LUT4 input	LUT4 output	Logic cell LUT4 combinational logic propagation delay, regardless of logic complexity from input to output.	0.48	ns
<b>t<sub>LUT4IN</sub></b>	LUT4 output	PIO output	Asynchronous delay from adjacent PLB interconnect to PIO output pad.	5.1	ns

## Programmable Input/Output (PIO) Block

Table 9 provides timing information for the logic in a Programmable Logic Block (PLB), which includes the paths shown in Figure 7 and Figure 8. The timing shown is for the LVCMOS25 I/O standard in all I/O banks. The iCEcube2 development software reports timing adjustments for other I/O standards.

Figure 7: Programmable I/O (PIO) Pad-to-Pad Timing Circuit

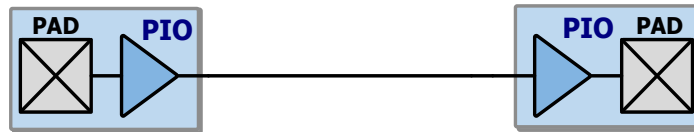


Figure 8: Programmable I/O (PIO) Sequential Timing Circuit

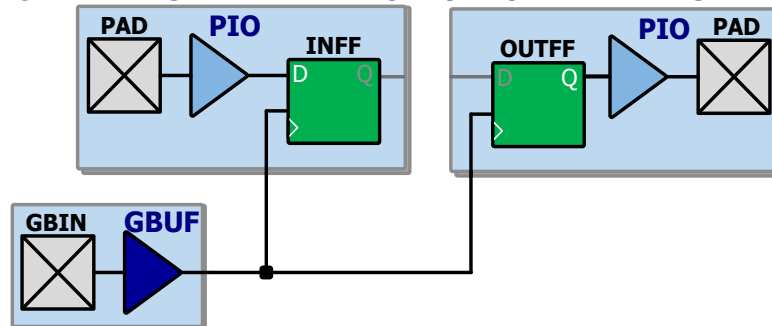


Table 9: Typical Programmable Input/Output (PIO) Timing (LVCMOS25)

			Nominal VCC	1.2 V	units
Description				Typ.	
<b>Synchronous Output Paths</b>					
$t_{\text{Ocko}}$	OUTFF clock input	PIO output	Delay from clock input on OUTFF output flip-flop to PIO output pad.	4.3	ns
$t_{\text{GBCKIO}}$	GBIN input	OUTFF clock input	Global Buffer Input (GBIN) delay, through Global Buffer (GBUF) clock network to clock input on the PIO OUTFF output flip-flop.	2.0	ns
<b>Synchronous Input Paths</b>					
$t_{\text{SUPDIN}}$	PIO input	GBIN input	Setup time on PIO input pin to INFF input flip-flop before active clock edge on GBIN input, including interconnect delay.	0	ns
$t_{\text{HDPDIN}}$	GBIN input	PIO input	Hold time on PIO input to INFF input flip-flop after active clock edge on the GBIN input, including interconnect delay.	2.2	ns
<b>Pad to Pad</b>					
$t_{\text{PADIN}}$	PIO input	Inter-connect	Asynchronous delay from PIO input pad to adjacent interconnect.	2.5	ns
$t_{\text{PADO}}$	Inter-connect	PIO output	Asynchronous delay from adjacent interconnect to PIO output pad including interconnect delay.	4.8	ns

**RAM4K Block**

Table 10 provides timing information for the logic in a RAM4K block, which includes the paths shown in Figure 9.

Figure 9: RAM4K Timing Circuit

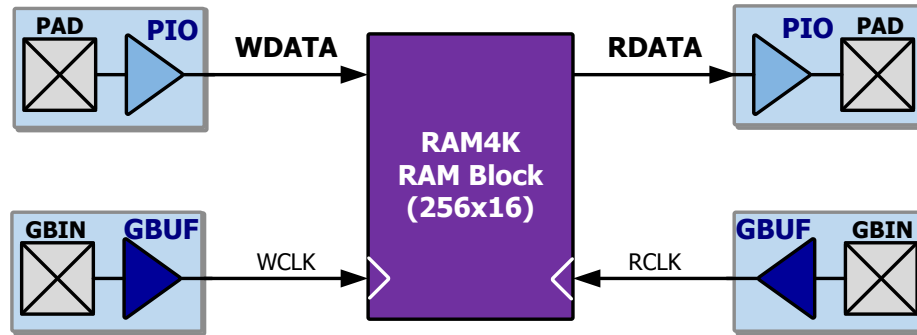


Table 10: Typical RAM4K Block Timing

			Nominal VCC	1.2 V	
Description				Typ.	
<b>Write Setup/Hold Time</b>					
$t_{SUWD}$	PIO input	GBIN input	Minimum write data setup time on PIO inputs before active clock edge on GBIN input, include interconnect delay.	0.62	ns
$t_{HDWD}$	GBIN input	PIO input	Minimum write data hold time on PIO inputs after active clock edge on GBIN input, including interconnect delay.	0	ns
<b>Read Clock-Output-Time</b>					
$t_{CKORD}$	RCLK clock input	PIO output	Clock-to-output delay from RCLK input pin, through RAM4K RDATA output flip-flop to PIO output pad, including interconnect delay.	5.6	ns
$t_{GBCKRM}$	GBIN input	RCLK clock input	Global Buffer Input (GBIN) delay, though Global Buffer (GBUF) clock network to the RCLK clock input.	2.0	ns
<b>Write and Read Clock Characteristics</b>					
$t_{RMWCKH}$	WCLK	WCLK	Write clock High time	0.42	ns
$t_{RMWCKL}$	RCLK	RCLK	Write clock Low time	0.48	ns
$t_{RMWCYC}$			Write clock cycle time	0.98	ns
$F_{WMAX}$			Sustained write clock frequency	256	MHz



## Phase-Locked Loop (PLL) Block

Table 11 provides timing information for the Phase-Locked Loop (PLL) block shown in Figure 10.

Figure 10: Phase-Locked Loop (PLL)

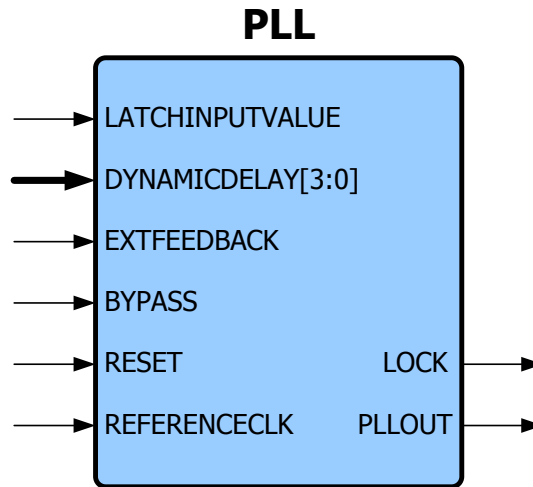


Table 11: Phase-Locked Loop (PLL) Block Timing

Symbol	From	To	Description	Nominal VCC			Units
				Min.	1.2 V Typical	Max.	
<b>Frequency Range</b>							
<b>F<sub>REF</sub></b>			Input clock frequency range	10	—	133	MHz
<b>F<sub>OUT</sub></b>			Output clock frequency range (cannot exceed maximum frequency supported by global buffers)	16	—	533	MHz
<b>Duty Cycle</b>							
<b>PLL<sub>IJ</sub></b>			Input duty cycle	35	—	65	%
<b>TW<sub>HI</sub></b>			Input clock high time	2.5	—	—	ns
<b>TW<sub>LOW</sub></b>			Input clock low time	2.5	—	—	ns
<b>PLL<sub>OJ</sub></b>			Output duty cycle	45	—	55	%
<b>Fine Delay</b>							
<b>t<sub>FDTAP</sub></b>			Fine delay adjustment, per tap		165		ps
<b>PLL<sub>TAPS</sub></b>			Fine delay adjustment settings	0	—	15	taps
<b>PLL<sub>FDAM</sub></b>			Maximum delay adjustment		2.5		ns
<b>Jitter</b>							
<b>PLL<sub>IPJ</sub></b>			Input clock period jitter	—	—	+/- 300	ps
<b>PLL<sub>OPJ</sub></b>			PLL <sub>OUT</sub> output period jitter	—	1% or ≤ 100	+/- 1.1% output period or ≥ 110	ps
<b>Lock/Reset Time</b>							
<b>t<sub>LOCK</sub></b>			PLL lock time after receive stable, monotonic REFERENCECLK input	—	—	50	μs
<b>tW<sub>RST</sub></b>			Minimum reset pulse width	20	—	—	ns

Notes:

- Output jitter performance is affected by input jitter. A clean reference clock < 100ps jitter must be used to ensure best jitter performance.
- The output jitter specification refers to the intrinsic jitter of the PLL.

## Internal Configuration Oscillator Frequency

Table 12 shows the operating frequency for the iCE40's internal configuration oscillator.

Table 12: Internal Oscillator Frequency at VCC = 1.2V

Symbol	Oscillator Mode	Frequency (MHz)		Description
		Min.	Max.	
f <sub>OSCD</sub>	<b>Default</b>	7	10	Default oscillator frequency. Slow enough to safely operate with any SPI serial PROM.
f <sub>OSCL</sub>	<b>Low Frequency</b>	21	30	Supported by most SPI serial Flash PROMs
f <sub>OSCH</sub>	<b>High Frequency</b>	35	50	Supported by some high-speed SPI serial Flash PROMs
	<b>Off</b>	0	0	Oscillator turned off by default after configuration to save power.

## Configuration Timing

Table 13 shows the maximum time to configure an iCE40LP device, by oscillator mode. The calculations use the slowest frequency for a given oscillator mode from Table 12 and the maximum configuration bitstream size from Table 1, which includes full RAM4K block initialization. The configuration bitstream selects the desired oscillator mode based on the performance of the configuration data source.

Table 13: Typical SPI Master or NVCM Configuration Timing by Oscillator Mode

Symbol	Description	Device	Default	Low Freq.	High Freq.	Units
t <sub>CONFIGL</sub>	Time from when minimum Power-on Reset (POR) threshold is reached until user application starts.	iCE40LP640	53	25	11	ms
		iCE40LP1K	53	25	11	ms
		iCE40LP4K	230	110	50	ms
		iCE40LP8K	230	110	50	ms

Table 14 provides timing for the CRESET\_B and CDONE pins.

Table 14: General Configuration Timing

Symbol	From	To	Description	All Grades		Units
				Min.	Max.	
t <sub>CRESET_B</sub>	CRESET_B	CRESET_B	Minimum CRESET_B Low pulse width required to restart configuration, from falling edge to rising edge	200	—	ns
t <sub>DONE_IO</sub>	CDONE High	PIO pins active	Number of configuration clock cycles after CDONE goes High before the PIO pins are activated.	—	49	Clock cycles
			SPI Peripheral Mode (Clock = SPI_SCK, cycles measured rising-edge to rising-edge)	Depends on SPI_SCK frequency		

Table 15 provides various timing specifications for the SPI peripheral mode interface.

Table 15: SPI Peripheral Mode Timing

Symbol	From	To	Description	All Grades		Units
				Min.	Max.	
t <sub>CR_SCK</sub>	CRESET_B	SPI_SCK	Minimum time from a rising edge on CRESET_B until the first SPI write operation, first SPI_SCK. During this time, the iCE40LP FPGA is clearing its internal configuration memory	300	—	µs
t <sub>SUSPISI</sub>	SPI_SI	SPI_SCK	Setup time on SPI_SI before the rising SPI_SCK clock edge	12	—	ns
t <sub>HDSPISI</sub>	SPI_SCK	SPI_SI	Hold time on SPI_SI after the rising SPI_SCK clock edge	12	—	ns
t <sub>SPISCKH</sub>	SPI_SCK	SPI_SCK	SPI_SCK clock High time	20	—	ns
t <sub>SPISCKL</sub>	SPI_SCK	SPI_SCK	SPI_SCK clock Low time	20	—	ns
t <sub>SPISCKCYC</sub>	SPI_SCK	SPI_SCK	SPI_SCK clock period*	40	1,000	ns
f <sub>SPI_SCK</sub>	SPI_SCK	SPI_SCK	Sustained SPI_SCK clock frequency*	1	25	MHz

\* = Applies after sending the synchronization pattern.

## Power Consumption Characteristics

### Core Power

Table 16 shows the power consumed on the internal VCC supply rail when the device is filled with 16-bit binary counters, measured with a 32.768 kHz and at 32.0 MHz

**Table 16: VCC Power Consumption for Device Filled with 16-Bit Binary Counters**

Symbol	Description	VCC	iCE40LP640	iCE40LP1K	iCE40LP4K	iCE40LP8K	Units
			Typical	Typical	Typical	Typical	
<b>I<sub>CC0K</sub></b>	f = 0	1.2V	35	40	140	160	μA
<b>I<sub>CC32K</sub></b>	f ≤ 32.768 kHz	1.2V	39	44	156	178	μA
<b>I<sub>CC32M</sub></b>	f = 32.0 MHz	1.2V	3	3	11	12	mA

### I/O Power

Table 17 provides the static current by I/O bank. The typical current for I/O Banks 0, 1, 2 and the SPI bank is not measurable within the accuracy of the test environment. The PIOs in I/O Bank 3 use different circuitry and dissipate a small amount of static current.

**Table 17: I/O Bank Static Current (f = 0 MHz)**

Symbol	Description	Typical	Maximum	Units
<b>I<sub>CC0_0</sub></b>	I/O Bank 0	Static current consumption per I/O bank. f = 0 MHz. No PIO pull-up resistors enabled. All inputs grounded. All outputs driving Low.	« 1	μA
<b>I<sub>CC0_1</sub></b>	I/O Bank 1		« 1	μA
<b>I<sub>CC0_2</sub></b>	I/O Bank 2		« 1	μA
<b>I<sub>CC0_3</sub></b>	I/O Bank 3		« 1	μA
<b>I<sub>CC0_SPI</sub></b>	SPI Bank		« 1	μA

NOTE: The typical static current for I/O Banks 0, 1, 2, and the SPI bank is less than the accuracy of the device tester.

### Power Estimator

To estimate the power consumption for a specific application, please download and use the iCE40LP Power Estimator Spreadsheet or use the power estimator built into the iCEcube2 software.

## Revision History

Version	Date	Description
<b>1.31</b>	30-MAR-2012	Updated <a href="#">Table 1</a>
<b>1.3</b>	22-MAR-2012	Production Release. Updated Notes on <a href="#">Table 3: Recommended Operating Conditions</a> Updated values in <a href="#">Table 4</a> , <a href="#">Table 5</a> , <a href="#">Table 12</a> , <a href="#">Table 13</a> and <a href="#">Table 17</a>
<b>1.21</b>	5-MAR-2012	Updated <a href="#">Figure 3</a> and <a href="#">Figure 4</a> to specify iCE40
<b>1.2</b>	13-FEB-2012	Updated company name
<b>1.1</b>	15-DEC-2011	Moved package specifications to iCE40 Pinout Excel files. Updated <a href="#">Table 1</a> maximum IOs.
<b>1.01</b>	31-OCT-2011	Added 640, 1K and 4K to <a href="#">Table 13</a> configuration times. Updated <a href="#">Table 1</a> maximum IOs.
<b>1.0</b>	11-JUL-2011	Initial Release

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